

650V N-Channel Super Junction Power MOSFET

DESCRIPTION

The **65R099F** use advanced super junction technology and design to provide excellent $R_{DS(ON)}$ with low gate charge, which leads to extremely communication and conduction losses .So it is very suitable for AC/DC power conversion, Laptop adapter Lighting, and industrial power applications.

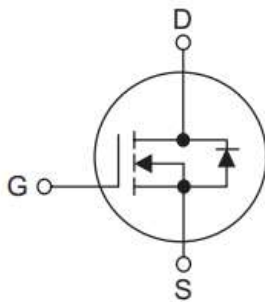
FEATURES

- *New technology for high voltage device
- *Ultra low Gate Charge
- *Ultra low Crss
- *Low gate charge



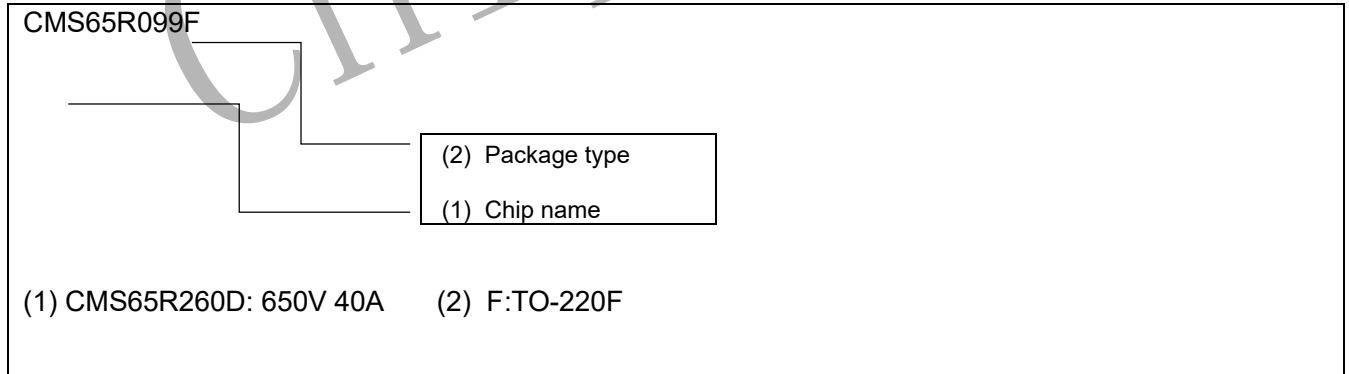
SYMBOL

1. Gate
2. Drain
3. Source



Package Description

Product Model	Package Type	Mark Name	Indentification Code	Package
CMS65R099F	TO-220F	CMS65R099	F	Tube



ABSOLUTE MAXIMUM RATINGS ($T_c = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	650	V
Gate-Source Voltage		V_{GSS}	± 30	V
Drain Current	Continuous($T_c=25^\circ\text{C}$)	I_D	40	A
Drain Current	Pulsed (Note1)	I_{DM}	120	A
Avalanche Energy	Single Pulsed (Note2)	E_{AS}	1000	mJ
Power Dissipation	$T_c=25^\circ\text{C}$ TO-220F	P_D	35	W
Junction Temperature		T_J	+150	$^\circ\text{C}$
Storage Temperature		T_{STG}	-55~+150	$^\circ\text{C}$

Notes:

- Limited by maximum junction temperature, maximum duty cycle is 0.75.
- $I_{AS} = 8\text{A}$, $V_{DD} = 60\text{V}$, Starting $T_J = 25^\circ\text{C}$.

THERMAL CHARACTERISTICS

Symbol	Parameter	PACKAGE	RATINGS	Units
$R_{\theta JC}$	Junction-to-Case	TO-220F	3.6	$^\circ\text{C}/\text{W}$
$R_{\theta JA}$	Junction-to-Ambient	TO-220F	62.5	$^\circ\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	$B_{V_{DS}}$	$V_{GS} = 0\text{ V}, I_D = 250\mu\text{A}$	650			V	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 650\text{ V}, V_{GS} = 0\text{ V}$			1	μA	
Gate-Source Leakage Current	Forward	I_{GSS}			100	nA	
	Reverse						$V_{GS} = 30\text{ V}, V_{DS} = 0\text{ V}$
					-100	nA	
ON CHARACTERISTICS							
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	2.0	3.0	4.0	V	
Static Drain-Source On- Resistance	$R_{DS(ON)}$	$V_{GS} = 10\text{ V}, I_D = 20\text{A}$		86	99	$\text{m}\Omega$	
DYNAMIC CHARACTERISTICS							
Input Capacitance	C_{ISS}	$V_{DS} = 25\text{ V}, V_{GS} = 0\text{V}$ $f = 1.0\text{MHz}$		3000		pF	
Output Capacitance	C_{OSS}				2500		pF
Reverse Transfer Capacitance	C_{RSS}				10		pF
SWITCHING CHARACTERISTICS							
Total Gate Charge	Q_G	$V_{DS} = 400\text{V}, I_D = 20\text{A},$ $V_{GS} = 10\text{V}$		66		nC	
Gate-Source Charge	Q_{GS}			17.8		nC	
Gate-Drain Charge	Q_{GD}			25		nC	
Turn-On Delay Time	$t_{D(ON)}$	$V_{DS} = 400\text{V}, I_D = 20\text{A},$ $R_G = 10\Omega, V_{GS} = 10\text{V}$		31.2		ns	
Turn-On Rise Time	t_R			43.8		ns	
Turn-Off Delay Time	$t_{D(OFF)}$			151.4		ns	
Turn-Off Fall Time	t_F			12.3		ns	
Drain-Source Diode Characteristics and Maximum Ratings							
Maximum Continuous Drain-Source Diode Forward Current	I_{SD}				40	A	
Maximum Pulsed Drain-Source Diode Forward Current	I_{SM}				120	A	
Drain-Source Diode Forward Voltage	V_{SD}	$V_{GS} = 0\text{ V}, I_F = 20\text{A}$			1.2	V	
Reverse Recovery Time	t_{rr}	$V_R = 50\text{V}, I_F = 20\text{A}$ $di_F/dt = 100\text{ A}/\mu\text{s}$		198		ns	
Reverse Recovery Charge	Q_{rr}				3.1		μC

ELECTRICAL CHARACTERISTICS DIAGRAMS

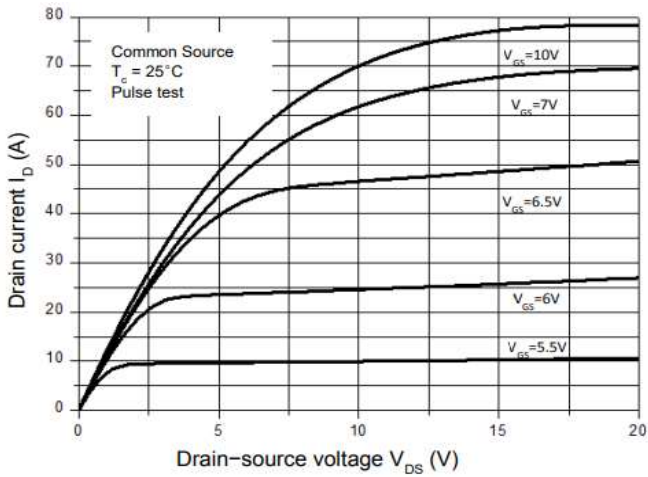


Figure 1. On-Region Characteristics

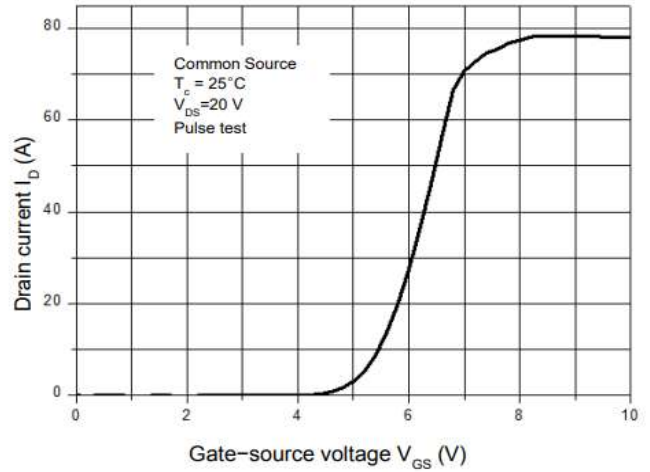


Figure 2. Transfer Characteristics

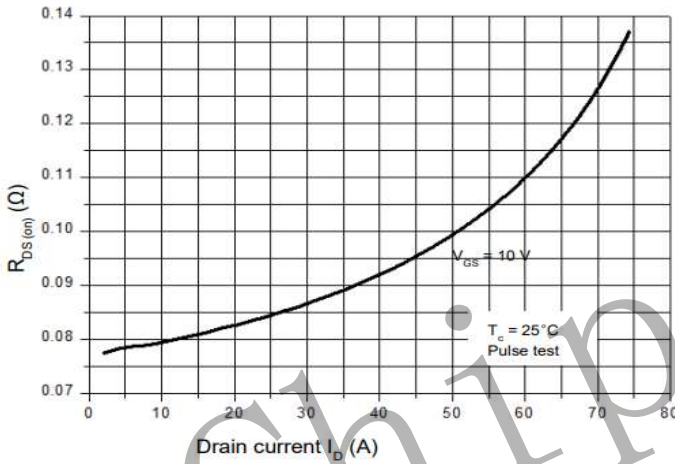


Figure 3. On-Resistance Variation vs. Drain Current

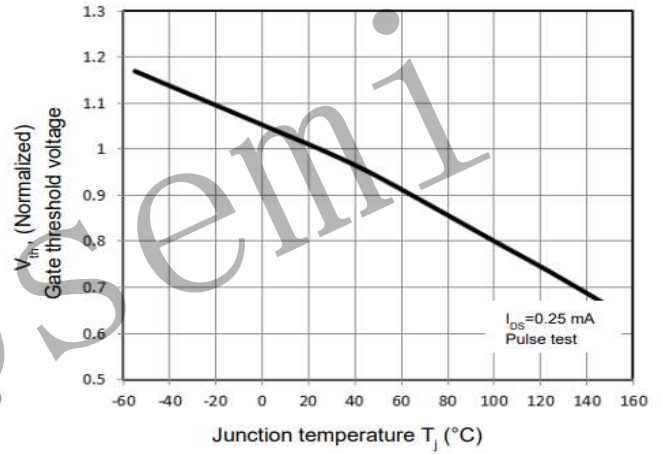


Figure 4. Threshold Voltage vs. Temperature

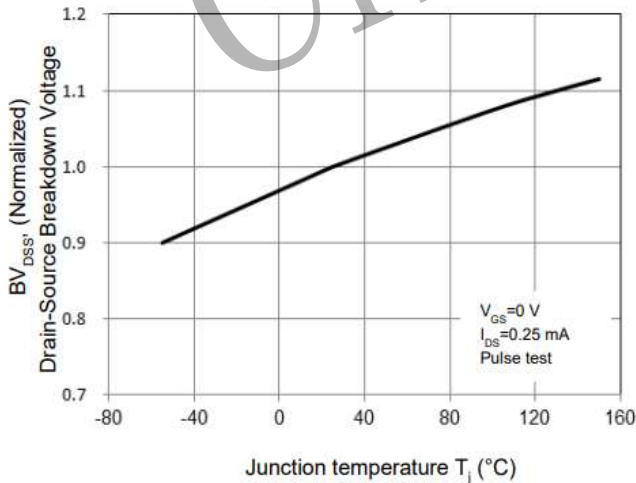


Figure 5. Breakdown Voltage vs. Temperature

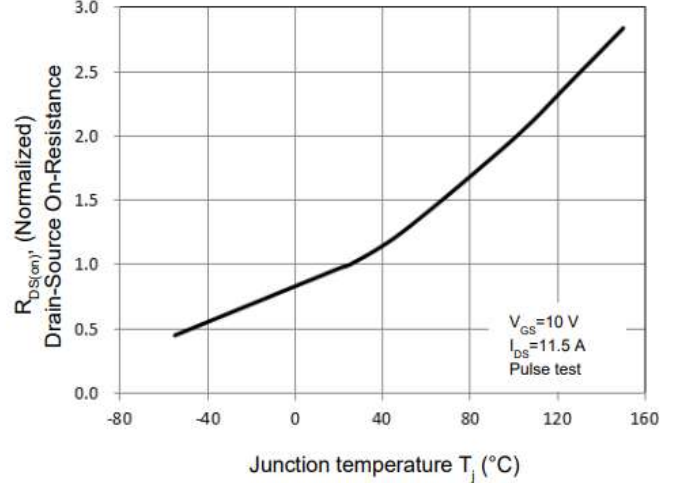


Figure 6. On-Resistance vs. Temperature

ELECTRICAL CHARACTERISTICS DIAGRAMS (Cont.)

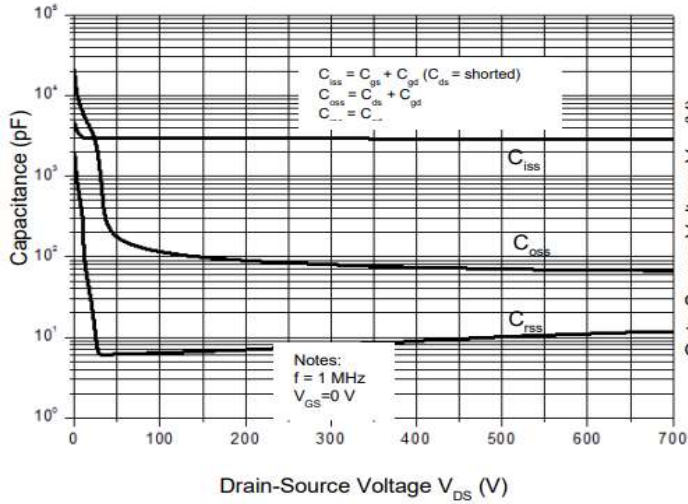


Figure 7. Capacitance Characteristics

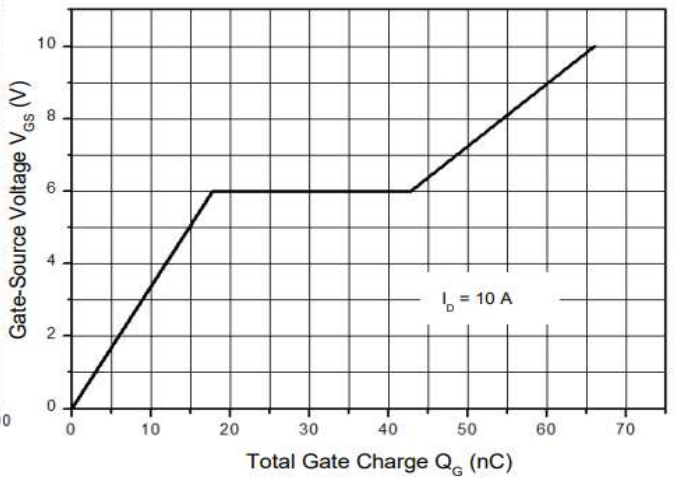


Figure 8. Gate Charge Characterist

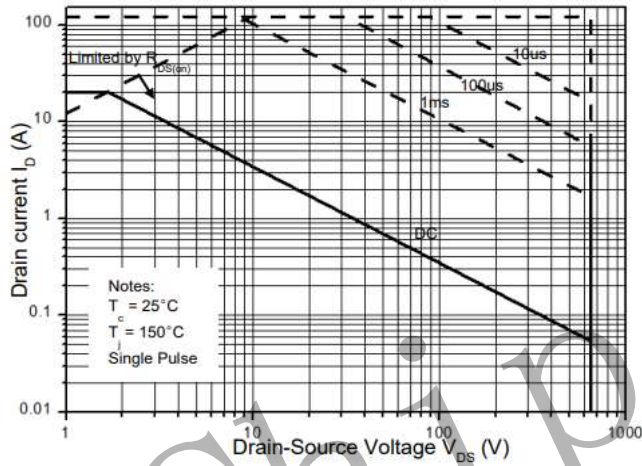


Figure 9. Maximum Safe Operating Area

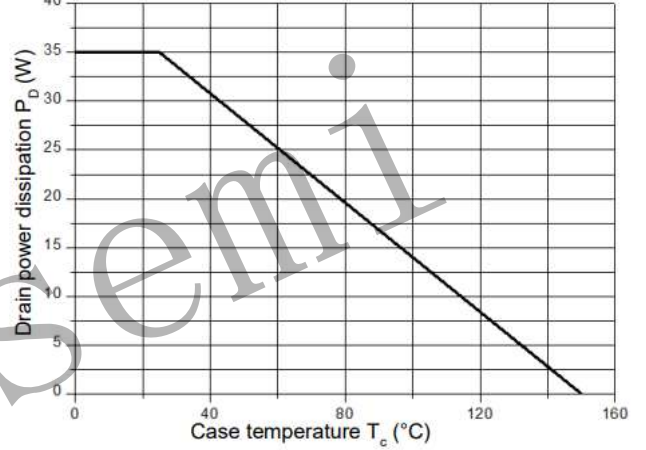
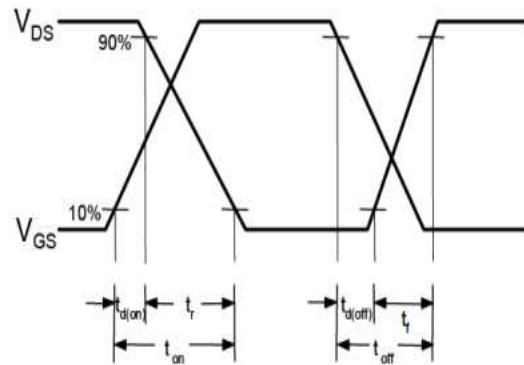
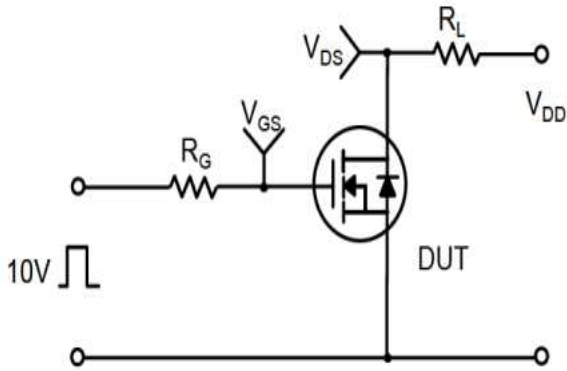
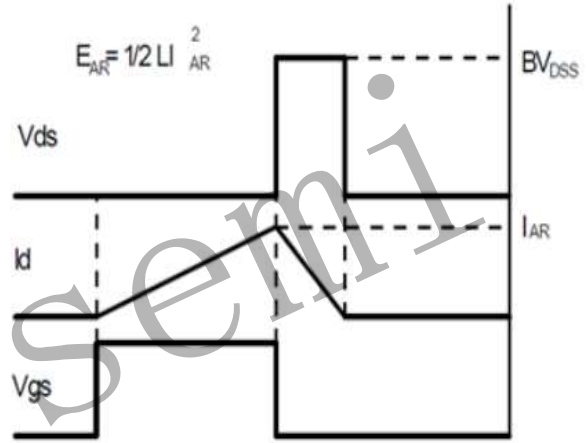
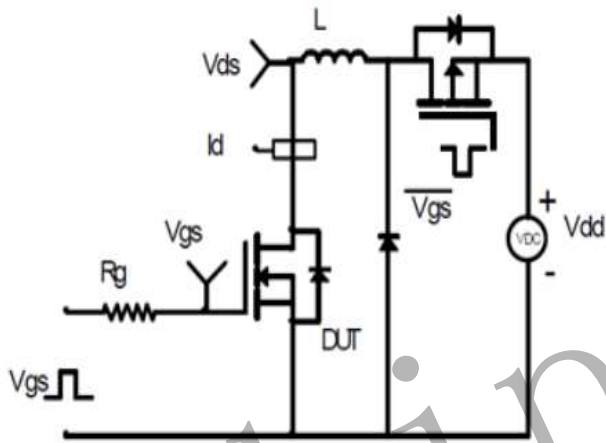


Figure 10. Power Dissipation vs. Temperature

TEST CIRCUITS



Unclamped Inductive Switching Test Circuit & Waveforms



Attentions

- Exceeding the maximum ratings of the device in performance may cause damage to the device, even the permanent failure, which may affect the dependability of the machine. Please do not exceed the absolute maximum ratings of the device when circuit designing.
- When installing the heat sink, please pay attention to the torsional moment and the smoothness of the heat sink.
- MOSFET is the device which is sensitive to the static electricity, it is necessary to protect the device from being damaged by the static electricity when using it.
- Chipsemi reserves the right to make changes in this specification sheet and is subject to change without prior notice.

Appendix

Revision history:

Date	REV.	Description	Page
2023.3	1.0	Original	7

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